

TW-P006

## Photoluminescence Studies of ZnO Nanostructures Fabricated by Using Combination of Hydrothermal Method and Plasma-Assisted Molecular Beam Epitaxy Regrowth

Giwoong Nam<sup>1</sup>, Byunggu Kim<sup>2</sup>, Youngbin Park<sup>2</sup>, Soaram Kim<sup>1</sup>,  
Sang-heon Lee<sup>3</sup>, Jong Su Kim<sup>4</sup>, Jae-Young Leem<sup>1,2\*</sup>

<sup>1</sup>Department of Nano Systems Engineering, Center for Nano Manufacturing, Inje University, Gimhae, Gyungnam 621-749, <sup>2</sup>Department of Nano Engineering, Inje University, Gimhae, Gyungnam 621-749, <sup>3</sup>School of Chemical Engineering, Yeungnam University, Gyeongsan 712-749, <sup>4</sup>Department of Physics, Yeungnam University, Gyeongsan 712-749, Korea

ZnO nanostructure was fabricated on a Si substrate using two-step growth. The seed layer was grown on the Si substrate by a sol-gel spin-coating. In the first step, ZnO nanorods were grown by a hydrothermal method at 140°C for 5 min. In the second step, a ZnO thin film was grown on the ZnO nanorods by spin-coating. After growth, these films were annealed at 800°C for 10 min. Electrical and optical properties of ZnO nanostructures have modified by plasma-assisted molecular beam epitaxy (PA-MBE) regrowth. The carrier concentration and resistivity increased by PA-MBE regrowth. In the photoluminescence, the full width at half maximum and intensity were decreased and increased, respectively, by PA-MBE regrowth.

**Keywords:** ZnO, Molecular beam epitaxy, Photoluminescence

TW-P007

## Synthesis and Temperature-Dependent Local Structural Properties of Ti<sub>2</sub>O<sub>3</sub>

Inhui Hwang<sup>1</sup>, Zhenlan Jin<sup>1</sup>, Changin Park<sup>1</sup>, Bingzhi Jiang<sup>2</sup>, S.-W. Han<sup>1\*</sup>

<sup>1</sup>Department of Physics Education and Institute of Fusion Science, Chonbuk National University, Jeonju 561-756, Korea, <sup>2</sup>Department of Physics, Yanbian University, Yanji 133002, China

Ti<sub>2</sub>O<sub>3</sub> is known as a typical Mott insulator with a transition temperature of near 200°C. Unlike VO<sub>2</sub>, Ti<sub>2</sub>O<sub>3</sub> does not have a structural phase transition near the metal-insulator-transition (MIT) temperature. We investigated the temperature-dependent thermal vibration change using temperature-dependent x-ray absorption fine structure (XAFS) at Ti K-edge in the temperature range of 300~600 K. Ti<sub>2</sub>O<sub>3</sub> powder and films were synthesized using thermal chemical vapor deposition (CVD) at 800~900°C. X-ray diffraction measurements show a single phased Ti<sub>2</sub>O<sub>3</sub> at room temperature. XAFS confirmed no structural phase transition in the temperature of 300~600 K. A small but distinguishable structural disorder change was observed near the transition temperature. We will discuss the MIT behavior with the change of structural disorder.

**Keywords:** Ti<sub>2</sub>O<sub>3</sub>, disorder, MIT, structure